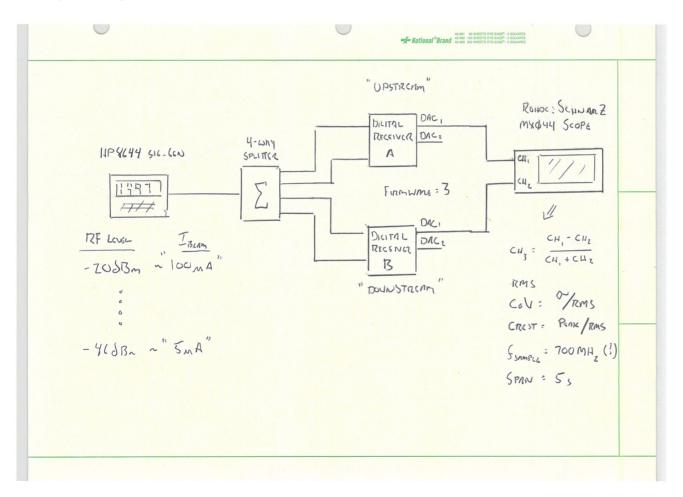
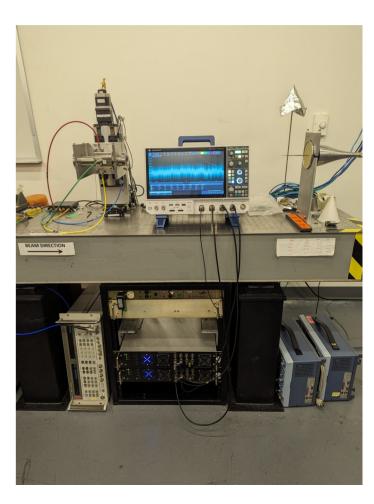
Input signals band-limited to 20 MHz





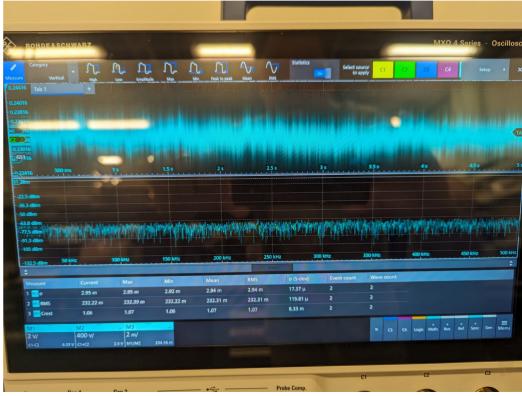
5 Second Time Span (500 ms/div)

$$\frac{Rx_A - Rx_B}{Rx_A + Rx_B}$$



...with spectrum to 1 MHz





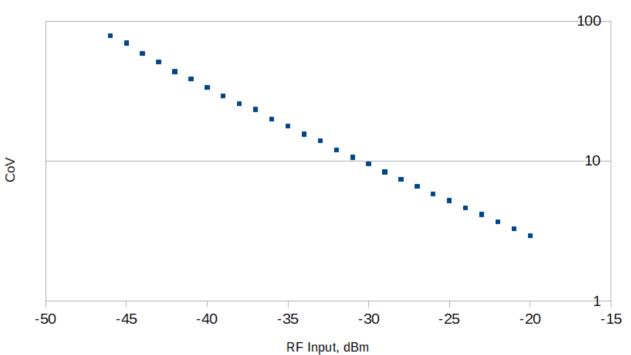
Coefficient of Variance vs RF Input

(Representing Beam Currents from 5-100 uA)

50 Ohm Test Load on Ch1 and Ch2:

CoV = 261.16 RMS = 324.72 C.F. = 128

...well within the measurement range



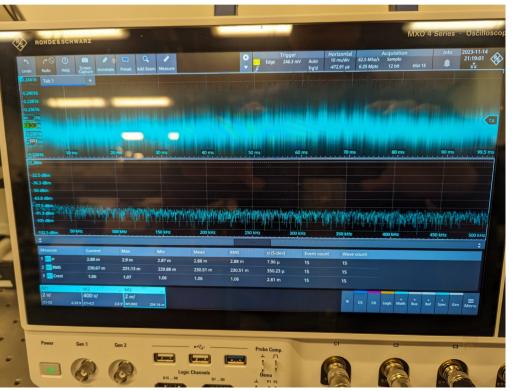
100 m-Second Time Span (10 ms/div)

$$\frac{Rx_A - Rx_B}{Rx_A + Rx_B}$$



...with spectrum to 1 MHz





10 m-Second Time Span (1 ms/div)

$$\frac{Rx_A - Rx_B}{Rx_A + Rx_B}$$

...with spectrum to 1 MHz

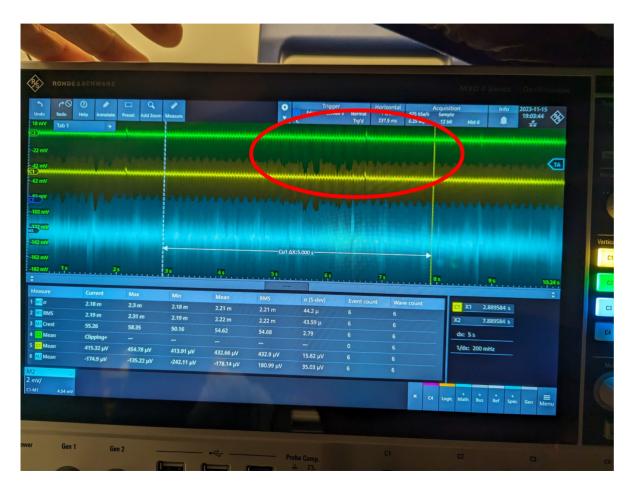


...with spectrum to 15 kHz





Measurements with Devi

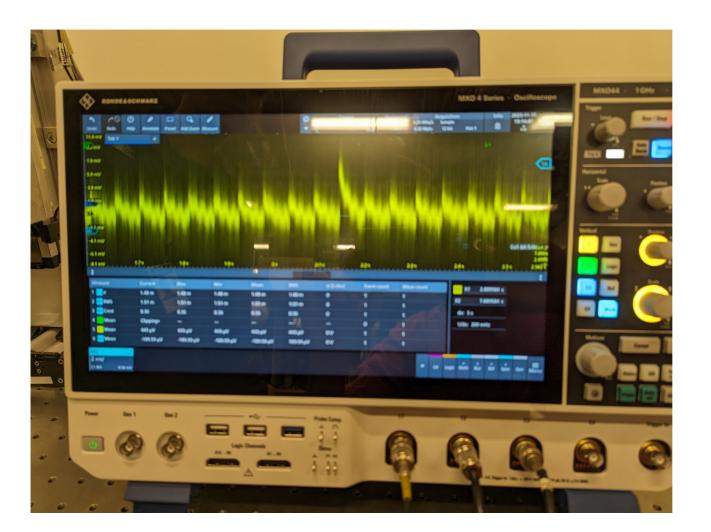


RF ramp: -22.2 dBm to -20.2 dBm 0.01 dB steps

Ch B (a/c coupled, 5mV/)

Ch A (a/c coupled, 5mV/)

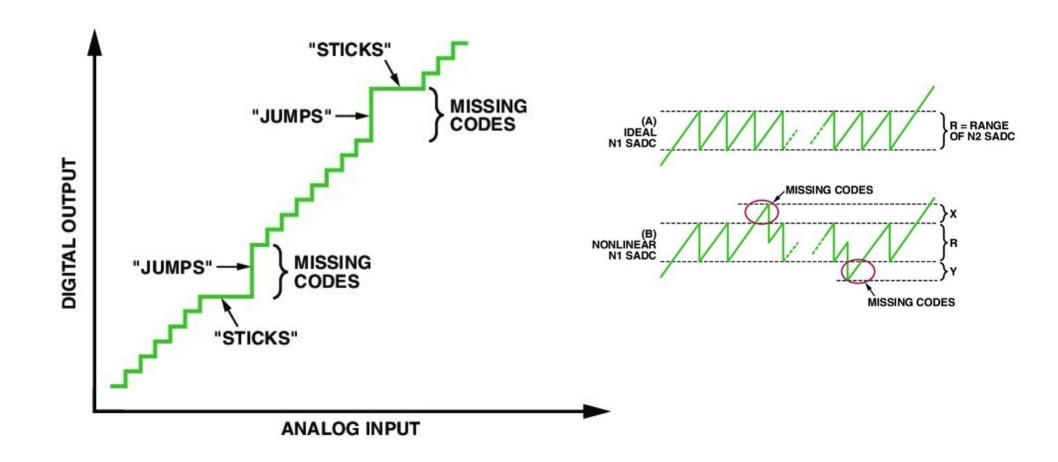
Ch A - Ch B (2 mV/)



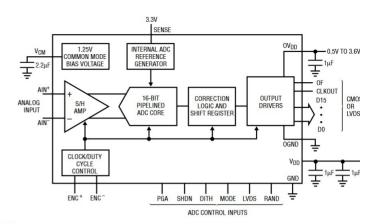
"Blip" occurs in same locations, and very close to Devi's receivers.

We are using the Unser firmware, so this suggests something ADC/DAC related?

Possible (likely?) Issue: INL, DNL



LTC2208:



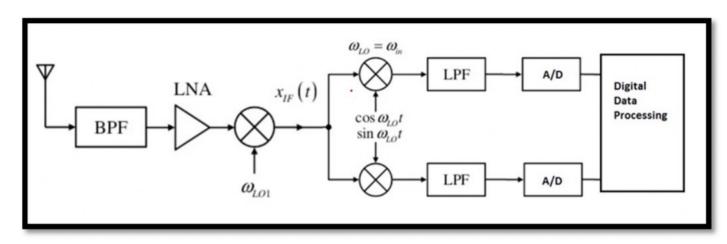
CONVERTER CHARACTERISTICS The \bullet denotes the specifications which apply over the full operating temperature range, otherwise specifications are at $T_A = 25$ °C. (Note 4)

PARAMETER CONDITIONS MIN TYP MAX UNITS Integral Linearity Error Differential Analog Input (Note 5) T_A = 25°C ±1.2 ±4.0 LSB Integral Linearity Error Differential Analog Input (Note 5) ±1.5 ±4.5 LSB Differential Linearity Error Differential Analog Input LSB ±0.3 Offset Error ±2 mV (Note 6) Offset Drift ±10 ··V//°C Gain Error External Reference ±0.2 ±1.5 %FS Full-Scale Drift Internal Reference ±30 ppm/°C External Reference ±15 ppm/°C **Transition Noise External Reference** 2.9 LSB_{RMS}

2208fb



If True....At Least for ADC.....



Consider a non-zero IF architecture....

Input RF rolls through all ADC codes...homogenizing the output I/Q values

...avoids "hammering" same spot on the ADC.

Perhaps consider Max's dithering for ADC and DAC?

